

Amendments to the Claims:

Please cancel claims 18 and 19, which stand withdrawn from consideration without prejudice or disclaimer of the subject matter thereof, and without prejudice to the right to file a divisional application directed thereto and add the following new claim.

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claims 1-10 (Cancelled)

11. (previously presented) A semiconductor processing apparatus comprising:

a chamber in which a sample wafer as a processing object is processed;

first and second data storing devices each receiving and storing data from said chamber which is generated during processing of said sample wafer, said data including data concerning emission light generated within said chamber during said processing; and

a selecting device which selectively sends said process data to one of said first and second data storing devices;

wherein said second data storing device enables reading said data stored in said second data storing device while said first data storing device stores said process data obtained from said chamber during processing of said sample wafer.

12. (previously presented) A semiconductor processing apparatus according to claim 11, wherein said first data storing device enables reading said data stored in said second data storing device while said first data storing device

stores said process data obtained from said chamber during processing of said sample wafer.

13. (previously presented) A semiconductor processing apparatus according to claim 11, further comprising:

a data analyzing device for analyzing said data stored in said first or second data storing device;

wherein while one of said first and second data storing devices stores the process data from said chamber, said data analyzing device performs analysis using the other of said first and second data storing devices.

14. (previously presented) A semiconductor processing apparatus according to claim 12, further comprising:

a data analyzing device for analyzing said data stored in said first or second data storing device;

wherein while one of said first and second data storing devices stores the process data from said chamber, said data analyzing device performs analysis using the other of said first and second data storing devices.

15. (previously presented) A semiconductor processing device according to claim 11, further comprising:

a diagnosis device for diagnosing an operation of said semiconductor processing apparatus using said data stored in said first or second data storing device;

wherein while one of said first and second data storing devices stores the process data from said chamber, said diagnosis device performs diagnosis using the other of said first and second data storing devices.

16. (previously presented) A semiconductor processing device according to claim 12, further comprising:

a diagnosis device for diagnosing an operation of said semiconductor processing apparatus using said data stored in said first or second data storing device;

wherein while one of said first and second data storing devices stores the process data from said chamber, said diagnosis device performs diagnosis using the other of said first and second data storing devices.

17. (previously presented) A data processing apparatus for said semiconductor processing device according to claim 11, wherein said first and second data storing devices are attachable to said semiconductor processing apparatus so as to be detachable therefrom and installable to said semiconductor apparatus.

Claims 18 and 19 (canceled)

20. (new) A semiconductor processing apparatus according to claim 11, wherein said selecting device including a data processor for receiving said process data from said chamber and being responsive to a storage change condition setting

device for sending said process data to one of said first and second data storing devices.